

Search Notes

Application/Control No.

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Examiner

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Applicant(s)/Patent under
Reexamination

LECLAIR, PHILIPPE

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	316	7/9/2007	JP
	295	7/9/2007	JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East USPAT/USPGPUB	7/9/2007	JP
Inventor Name Search	7/9/2007	JP
NPL Search IEEE Explore	7/9/2007	JP